

# DS1776QML

SNOSC82-AUGUST 2012

# **DS1776QML PI-Bus Transceiver**

Check for Samples: DS1776QML

# FEATURES

- Similar to BTL
- Low power I<sub>CCL</sub> = 41 mA max

- B output controlled ramp rate
- B input noise immunity, typically 4 ns
- Pin and function compatible with Signetics 54F776

# DESCRIPTION

The DS1776 is an octal PI-bus Transceiver. The A to B path is latched. B outputs are open collector with series Schottky diode, ensuring minimum B output loading. B outputs also have ramped rise and fall times (2.5 ns typical), ensuring minimum PI-bus ringing. B inputs have glitch rejection circuitry, 4 ns typical.

Designed using National's Bi-CMOS process for both low operating and disabled power. AC performance is optimized for the PI-Bus inter-operability requirements.

The DS1776 is an octal latched transceiver and is intended to provide the electrical interface to a high performance wired-or bus. This bus has a loaded characteristic impedance range of  $20\Omega$  to  $50\Omega$  and is terminated on each end with a  $30\Omega$  to  $40\Omega$  resistor.

The DS1776 is an octal bidirectional transceiver with open collector B and TRI-STATE<sup>®</sup> A port output drivers. A latch function is provided for the A port signals. The B port output driver is designed to sink 100 mA from 2V and features a controlled linear ramp to minimize crosstalk and ringing on the bus.

A separate high level control voltage ( $V_X$ ) is provided to prevent the A side output high level from exceeding future high density processor supply voltage levels. For 5V systems,  $V_X$  is tied to  $V_{CC}$ .

## **Connection Diagram**



Figure 1. Hermetic Leadless Chip Carrier

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# Logic Symbol



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## Absolute Maximum Ratings <sup>(1)</sup>

•					
Supply Voltage (V <sub>CC</sub> )	-0.5V to +7.0V				
V <sub>X</sub> , V <sub>OH</sub> Output Level Control Voltage (A Outputs)	-0.5V to +7.0V				
OEBn, OEA, LE Input Voltage (VI)	-0.5V to +7.0V				
A0–A7, B0–B7 Input Voltage (VI)	-0.5V to +5.5V				
Input Current (I <sub>I</sub> )	-40 mA to +5 mA				
Voltage Applied to Output in High Output State (V <sub>O</sub> )	$-0.5V$ to $+V_{CC}$				
A0-A7 Current Applied to Output in Low Output State (I <sub>O</sub> )	40 mA				
B0–B7 Current Applied to Output in Low Output State (I <sub>O</sub> )	200 mA				
Storage Temperature Range (T <sub>Stg</sub> )	$-65^{\circ}C \le T_{A} \le +150^{\circ}C$				
Thermal Resistance					
$\theta_{JA}$	+67.5°C				
θ <sub>JC</sub>	See MIL-STD-1835				
Lead Temperature (Soldering 10 Sec.)	260°C				
Power Dissipation <sup>(2)</sup>	740mW				
ESD Tolerance:	500 V				
$     \nabla_{7an} = 120  \mu \Gamma,  \nabla_{7an} = 1000  \Omega $					

(1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

(2) The maximum power dissipation must be derated at elevated temperatures and is dictated by T<sub>Jmax</sub> (maximum junction temperature), θ<sub>JA</sub> (package junction to ambient thermal resistance), and T<sub>A</sub> (ambient temperature). The maximum allowable power dissipation at any temperature is P<sub>Dmax</sub> = (T<sub>Jmax</sub> - T<sub>A</sub>)/θ<sub>JA</sub> or the number given in the Absolute Maximum Ratings, whichever is lower.

### **Recommend Operating Conditions**

	Min	Max	Units
Supply Voltage (V <sub>CC</sub> )	4.5	5.5	V
Operating Temp. Range (T <sub>A</sub> )	-55	+125	°C

### **Quality Conformance Inspection**

### Table 1. Mil-Std-883, Method 5005 - Group A

Subgroup	Description	Temp (°C)
1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25



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# Table 1. Mil-Std-883, Method 5005 - Group A

(continued)							
5	Dynamic tests at	+125					
6	Dynamic tests at	-55					
7	Functional tests at	+25					
8A	Functional tests at	+125					
8B	Functional tests at	-55					
9	Switching tests at	+25					
10	Switching tests at	+125					
11	Switching tests at	-55					
12	Settling time at	+25					
13	Settling time at	+125					
14	Settling time at	-55					

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## PI Bus Transceiver DS1776 DC Parameters

The following conditions apply, unless otherwise specified.  $V_{CC} = 5.5V$ 

Symbol	Parameter	Parameter Conditions Notes		Min	Max	Units	Sub- groups
V <sub>IL2</sub>	Low Level In Voltage Bn	V <sub>CC</sub> = 4.5	(1)		1.45	V	1, 2, 3
V <sub>IL1</sub>	All Other Inputs	V <sub>CC</sub> = 4.5			.8	V	1, 2, 3
V <sub>IH1</sub>	Hi Level Input Voltage OEBn, OEA, An, LE		(1)	2.0		V	1, 2, 3
V <sub>IH2</sub>	High Level In Voltage B0-B7			1.6		V	1, 2, 3
I <sub>OH1</sub>	High Level Output Current An		(2)		-3.0	mA	1, 2, 3
I <sub>OH2</sub>	High Level Output Current Bn	$ \begin{array}{l} V_{CC} = 5.5,  V_{IL} = 0.8 V, \\ V_{IH} = 2.0 V,  V_{OH} = 2.1 V \end{array} $			100	μA	1, 2, 3
I <sub>OL1</sub>	Low Level Output Current An		(3)		20	mA	1, 2, 3
I <sub>OL2</sub>	Low Level Output Current Bn				100	mA	1, 2, 3
		$\label{eq:V_CC} \begin{array}{l} V_{CC} = 4.5, \ V_{IN} = V_{IL} \ \text{or} \ V_{IH}, \\ I_{OH} = -3 \ \text{mA}, \ V_{X} = 4.5 V \end{array}$		2.5	4.5	V	1, 2, 3
V <sub>OH</sub>	High Level Output Voltage An	$ \begin{array}{l} V_{CC} = 4.5,  V_{IN} = V_{IL} \text{ or } V_{IH}, \\ I_{OH} = -0.4 \text{ mA}, \\ V_X = 3.13 \text{ to } 3.47 \text{V} \end{array} $		2.5	V <sub>X</sub>	V	1, 2, 3
V <sub>OL</sub>	Low Level Output Voltage An	$\label{eq:V_CC} \begin{array}{l} V_{CC} = 4.5,  V_{IL} = Max, \\ V_{IH} = Min,  I_{OL} = 20mA, \\ V_{X} = V_{CC} \end{array}$			0.5	V	1, 2, 3
V	Low Lovel Output Veltage Re	$V_{CC}$ = 4.5, $V_{IL}$ = Max, $V_{IH}$ = Min, $I_{OL}$ = 100mA			1.15	V	1, 2, 3
VOLB	Low Level Oulput voltage bit	$V_{CC}$ = 4.5, $V_{IL}$ = Max, $V_{IH}$ = Min, $I_{OL}$ = 4mA		0.4		V	1, 2, 3
V <sub>IK</sub>	Input Clamp Voltage An	$V_{CC} = 4.5, I_I = -40mA$			-0.5	V	1, 2, 3
V <sub>IK</sub>	Input Clamp Voltage Other Inputs	$V_{CC} = 4.5, I_I = -18mA$			-1.2	V	1, 2, 3
I <sub>IH1</sub>	Input Current Max Input Voltage OEBn, OEA, LE	$V_{CC} = 5.5, V_1 = 7.0V$			100	μA	1, 2, 3
I <sub>IH2</sub>	Input Current Max Input Voltage An, Bn	$V_{CC} = 5.5, V_1 = 5.5V$			1.0	mA	1, 2, 3
I <sub>IH3</sub>	High Level Input Current OEBn, OEA, LE	$V_{CC} = 5.5, V_1 = 2.7V$			20	μA	1, 2, 3
I <sub>IH4</sub>	High Level Input Current Bn	$V_{CC} = 5.5, V_I = 2.1V$			100	μΑ	1, 2, 3
I <sub>IL1</sub>	Low Level Input Current OEBn, OEA, Except OEBn or OEA	$V_{CC} = 5.5, V_{I} = 0.5V$			-20	μA	1, 2, 3
lu e	Low Level Input Current LE	$V_{00} = 5.5$ $V_{1} = 0.5V$			-20	μΑ	1
'IL2					-40	μA	2, 3
I <sub>IL3</sub>	Low Level Input Current Bn	$V_{CC} = 5.5, V_{I} = 0.3V$			-100	μΑ	1, 2, 3
I <sub>OZH</sub> + I <sub>IH</sub>	TRI-STATE Output Current, High Level Voltage Applied An	$V_{CC} = 5.5, V_{O} = 2.7V$			70	μA	1, 2, 3
I <sub>OZL</sub> + I <sub>IL</sub>	TRI-STATE Output Current, Low Level Voltage Applied An	$V_{CC} = 5.5, V_{O} = 0.5V$			-70	μA	1, 2, 3
		$\frac{V_{CC}}{LE} = 5.5, V_X = 5.5V,$ LE = OEA = OEBn = 2.7V, A0-A7 = 2.7, B0-B7 = 2V		-100	100	μΑ	1, 2, 3
I <sub>X</sub>	High Level Control Current	$V_{CC} = 5.5, B0-B7 = 2V$ $V_X = 3.13V \text{ and } 3.47V,$ LE = OEA = 2.7V, $\overline{OEBn} = A0-A7 = 2.7V,$		-10	10	mA	1, 2, 3

Tested Go-No-Go (1)

Same as  $V_{OL}$  test. Same as  $V_{OL}$  test. (2)

(3)

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**PRODUCT PREVIEW** 

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# PI Bus Transceiver DS1776 DC Parameters (continued)

The following conditions apply, unless otherwise specified.  $V_{CC} = 5.5V$ 

Symbol	Parameter	Conditions	Notes	Min	Max	Units	Sub- groups
I <sub>OS</sub>	Short Circuit Output Current A0- A7 only	$V_{CC} = 5.5, Bn = 1.9V,$ OEA = 2.0V, OEBn = 2.7V, $V_{O} = 0V$	(4)	-60	-150	mA	1, 2, 3
	Supply Current (Total)	(1 - 55) ((1 - 5)) = 50)			37	mA	1, 2
ССН	Supply Current (Total) I <sub>CCH</sub>	$v_{\rm CC} = 5.5, v_{\rm IN} (AII) = 5.0 v$			41	mA	3
	Supply Current (Total) I				38	mA	1, 3
ICCL	Supply Current (Total) I <sub>CCL</sub>	$v_{\rm CC} = 5.5, v_{\rm IN} (AII) = 0.5 v$			34	mA	2
I <sub>CCZ</sub>	Supply Current (Total) I <sub>CCZ</sub>	$V_{CC} = 5.5, V_{IN} (An) = 0.5V$			35	mA	1, 2, 3
I <sub>Off</sub>	Power Off Output Current B0-B7	$V_{CC} = 0$ , Bn = 2.1V, $V_{IL} = Max$ , $V_{IH} = Min$			100	μΑ	1, 2, 3

(4) Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter test, I<sub>OS</sub> tests should be performed last.

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# PI Bus Transceiver DS1776 AC Parameters: B to A Path

The following conditions apply, unless otherwise specified.  $~V_{CC}$  = 5V ±10%,  $C_L$  = 50pF,  $R_L$  = 500 $\Omega$ 

Symbol	Parameter	Conditions	Notes	Min	Max	Units	Sub- groups
t <sub>PLH</sub>	Propagation Delay B to A	Waveform 1, 2		4.5	17	ns	9, 10, 11
t <sub>PHL</sub>	Propagation Delay B to A	Waveform 1, 2		6.0	17	ns	9, 10, 11
t <sub>PZH</sub>	Output Enable OEA To A	Waveform 3, 4		4.0	17	ns	9, 10, 11
t <sub>PZL</sub>	Output Enable OEA To A	Waveform 3, 4		4.0	21	ns	9, 10, 11
t <sub>PHZ</sub>	Output Disable OEA to A	Waveform 3, 4		2.0	12	ns	9, 10, 11
t <sub>PLZ</sub>	Output Disable OEA to A	Waveform 3, 4		2.0	13	ns	9, 10, 11



# PI Bus Transceiver DS1776 AC Parameters: A to B Path

The following conditions apply, unless otherwise specified.  $~V_{CC}$  = 5V ±10%,  $C_L$  = 30pF,  $R_L$  = 9 $\Omega$ 

Symbol	Parameter Conditions Notes		Notes	Min	Max	Units	Sub- groups
	Propagation Dalay A to P	Moveform 1 2		2.0	13	ns	9, 11
<sup>L</sup> PLH	Propagation Delay A to B	vvavelonn 1, 2		2.0	17	ns	10
t <sub>PHL</sub>	Propagation Delay A to B	Waveform 1, 2		2.5	13	ns	9, 10, 11
t <sub>PLH</sub>	Propagation Delay LE to B	Waveform 1, 2		2.0	16	ns	9, 11
				2.0	22	ns	10
t <sub>PHL</sub>	Propagation Delay LE to B	Waveform 1, 2		2.0	16	ns	9, 10, 11
	Enchle / Dischle Time OFPn to D	Moveform 1 2		2.0	13	ns	9, 11
<sup>L</sup> PLH	Enable / Disable Time CEBH to B	vvavelonn 1, 2		2.0	16	ns	10
				3.5	14	ns	9
t <sub>PHL</sub>	Enable / Disable Time OEBn to B	Waveform 1, 2		3.5	13	ns	10
				3.5	16	ns	11

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# PI Bus Transceiver DS1776 AC Parameters: Setup / Hold / Pulse Width Specifications

The following conditions apply, unless otherwise specified.  $V_{CC} = 5V \pm 10\%$ 

Symbol	Parameter	Conditions	Notes	Min	Max	Units	Sub- groups
t <sub>S</sub>	A to LE Setup	Waveform 5		7.0		ns	9, 10, 11
t <sub>H</sub>	A to LE Hold	Waveform 5		0.0		ns	9, 10, 11
t <sub>W</sub>	LE Pulse Width Low	Waveform 5		12		ns	9, 10, 11

# Descriptions

### **Table 2. Pin Descriptions**

Symbol	Pins	Туре	Name and Function			
A0	3	I/O				
A1	5	I/O				
A2	6	I/O				
A3	7	I/O	TTL Level, latched input/TRI-STATE output (with V <sub>X</sub> control option)			
A4	9	I/O				
A5	10	I/O				
A6	12	I/O				
A7	13	I/O				
B0	27	I/O				
B1	26	I/O				
B2	24	I/O				
B3	23	I/O	Data input with special threshold circuitry to reject noise/Open Collector output, High			
B4	21	I/O	current drive			
B5	20	I/O				
B6	19	I/O				
B7	17	I/O				
OEB 0	15	I	Enables the B outputs when both pins are low			
OEB 1	16	Ι				
OEA	2	Ι	Enables the A outputs when High			
LE	28	Ι	Latched when High (a special delay feature is built in for proper enabling times)			
V <sub>X</sub>	14	I	Clamping voltage keeping $V_{OH}$ from rising above $V_X$ ( $V_X = V_{CC}$ for normal use)			



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 $V_{CC} = Pin 1$  $V_X = Pin 14$ Gnd = Pins 4, 8, 11, 18, 22, 25



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		Inp	uts			Latch	Οι	utputs	Mode			
An	Bn <sup>(1)</sup>	LE	OEA	OEB 0	OEB 1	State	An	Bn				
Н	х	L	L	L	L	н	Z	Н	A TRI-STATE, Data from A to B			
L	х	L	L	L	L	L	Z	L				
Х	Х	Н	L	L	L	Qn	Z	Qn	A TRI-STATE, Latched Data to B			
_	—	L	Н	L	L	(2)	(1)	(1)	Feedback: A to B, B to A			
_	Н	Н	Н	L	L	H <sup>(3)</sup>	Н	off <sup>(3)</sup>	Preconditioned Latch Enabling			
_	L	Н	Н	L	L	H <sup>(3)</sup>	L	off <sup>(3)</sup>	Data Transfer from B to A			
_	_	Н	н	L	L	Qn	Qn	Qn	Latch State to A and B			
н	Х	L	L	Н	Х	Н	Z	off				
L	Х	L	L	Н	Х	L	Z	off	B off and A TRI-STATE			
Х	Х	Н	L	Н	Х	Qn	Z	off				
_	Н	L	Н	Н	Х	н	Н	off				
—	L	L	н	н	х	L	L	off				
—	Н	Н	Н	Н	Х	Qn	Н	off	B off, Data from B to A			
—	L	Н	Н	Н	Х	Qn	L	off				
Н	Х	L	L	Х	Н	Н	Z	off				
L	Х	L	L	Х	н	L	Z	off	B off and A TRI-STATE			
Х	Х	Н	L	Х	Н	Qn	Z	off				
_	Н	L	Н	Х	Н	Н	Н	off				
_	L	L	Н	Х	Н	L	L	off	B off, Data from B to A			
_	Н	Н	Н	Х	Н	Qn	Н	off				
—	L	Н	Н	Х	Н	Qn	L	off				

 Table 3. Function Table

(1) Condition will cause a feedback loop path; A to B and B to A.

(2) Precaution should be taken to ensure that the B inputs do not float. If they do, they are equal to a Low state.

(3) The latch must be preconditioned such that B inputs may assume a High or Low level while OEB 0 and OEB 1, are Low and LE is high.

## CONTROLLER POWER SEQUENCING OPERATION

The DS1776 has a design feature which controls the output transitions during power up (or down). There are two possible conditions that occur.

- 1. When  $\overline{\text{LE}}$  = Low and  $\overline{\text{OEBn}}$  = Low, the B outputs are disabled until the  $\overline{\text{LE}}$  circuit can take control. This feature ensures that the B outputs will follow the A inputs and allow only one transition during power up (or down).
- 2. If  $\overline{\text{LE}}$  = High or  $\overline{\text{OEBn}}$  = High, then the B outputs still remain disabled during power up (or down).

## **Switching Characteristics**

### AC WAVEFORMS



Figure 3. Waveform 1: Propagation Delay for Data to Output

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The shaded areas indicate when the input is permitted to change for predictable output performance.

Figure 7. Waveform 5: Data Setup and Hold Times and LE Pulse Widths

### **TEST CIRCUIT AND WAVEFORMS**





#### Table 4. Switch Position

Test	Switch
t <sub>PLZ</sub> , t <sub>PZL</sub>	Closed
All Other	Open

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# Figure 9. Test Circuit for TRI-STATE Outputs on B Side



#### DEFINITIONS

 $R_L$  = Load resistor 500 $\Omega$ 

 $C_L$  = Load capacitance includes jig and probe capacitance

 $R_T$  = Termination resistance should be equal to  $Z_O$  of pulse generators.

R<sub>U</sub> = Pull up resistor

### Figure 10. Input Pulse Definition



	Input Pulse Characteristics							
	Amplitude	Low V	Rep. Rate	tw	t <sub>TLH</sub>	t <sub>THL</sub>		
A Side	3.0V	0.0V	1 MHz	500 ns	2 ns	2 ns		
B Side	2.0V	1.0V	1 MHz	500 ns	2 ns	2 ns		

### Table 5. Revision History

Released	Revision	Section	Changes
30–Jul-2012	А	New Release, Corporate format	1 MDS data sheet converted into one Corp. data sheet format. MNDS1776-X Rev 2A0. will be archived.



# PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Samples
	(1)		Drawing			(2)		(3)	(Requires Login)
5962-9231701M3A	ACTIVE	LCCC	FK	28	25	TBD	POST-PLATE	Level-1-NA-UNLIM	
DS1776E/883	ACTIVE	LCCC	FK	28	25	TBD	POST-PLATE	Level-1-NA-UNLIM	

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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LEADLESS CERAMIC CHIP CARRIER

FK (S-CQCC-N\*\*) 28 TERMINAL SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

- C. This package can be hermetically sealed with a metal lid.
- D. Falls within JEDEC MS-004



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